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| Notice of References Cited | Application/Control No. 10/596,843 | | Applicant(s)/Patent Under Reexamination TANAKA, HIDEO | |
| | Examiner LUCY P. CHIEN | | Art Unit 2871 | Page 1 of 1 |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|-----------------|----------------|
| * | A | US-6,407,791 | 06-2002 | Suzuki et al. | 349/129 |
| * | B | US-5,781,256 | 07-1998 | Inoue et al. | 349/51 |
| * | C | US-5,815,223 | 09-1998 | Watanabe et al. | 349/42 |
| * | D | US-2003/0174267 | 09-2003 | Nimura, Toru | 349/113 |
| * | E | US-2002/0158995 | 10-2002 | Hwang et al. | 349/43 |
| | F | US- | | | |
| | G | US- | | | |
| | H | US- | | | |
| | I | US- | | | |
| | J | US- | | | |
| | K | US- | | | |
| | L | US- | | | |
| | M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|------|----------------|
| | N | | | | | |
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| | P | | | | | |
| | Q | | | | | |
| | R | | | | | |
| | S | | | | | |
| | T | | | | | |

NON-PATENT DOCUMENTS

| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
|---|---|---|
| | U | |
| | V | |
| | W | |
| | X | |

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